SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

- Independent Registers for A and B Buses
- Multiplexed Real-Time and Stored Data
- Choice of True or Inverting Data Paths
- Choice of 3-State or Open-Collector Outputs
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (NT) and Ceramic (JT) 300-mil DIPs

DEVICE	OUTPUT	LOGIC
SN54ALS646, SN74ALS646A, 'AS646	3 state	True
SN54ALS648, SN74ALS648A, SN74AS648	3 state	Inverting

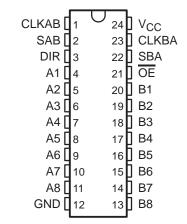
description

These devices consist of bus-transceiver circuits with 3-state or open-collector outputs, D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the data bus or from the internal storage registers. Data on the A or B bus is clocked into the registers on the low-to-high transition of the appropriate clock (CLKAB or CLKBA) input. Figure 1 illustrates the four fundamental bus-management functions that can be performed with the octal bus transceivers and registers.

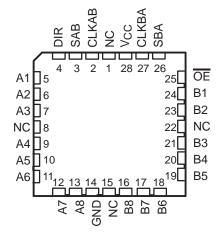
Output-enable (OE) and direction-control (DIR) inputs control the transceiver functions. In the transceiver mode, data present at the high-impedance port may be stored in either or both registers.

The select-control (SAB and SBA) inputs can multiplex stored and real-time (transparent mode)

SN54ALS646, SN54ALS648, SN54AS646 . . . JT PACKAGE SN74ALS646A, SN74ALS648A, SN74AS646, SN74AS648 . . . DW OR NT PACKAGE (TOP VIEW)



SN54ALS646, SN54ALS648, SN54AS646 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

data. The circuitry used for select control eliminates the typical decoding glitch that occurs in a multiplexer during the transition between stored and real-time data. DIR determines which bus receives data when \overline{OE} is low. In the isolation mode (\overline{OE} high), A data may be stored in one register and/or B data may be stored in the other register.

When an output function is disabled, the input function is still enabled and can be used to store and transmit data. Only one of the two buses, A or B, may be driven at a time.

The -1 version of the SN74ALS646A is identical to the standard version, except that the recommended maximum I_{OL} in the -1 version is increased to 48 mA. There are no -1 versions of the SN54ALS646, SN54ALS648A.

The SN54ALS646, SN54ALS648, and SN54AS646 are characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ALS646A, SN74ALS648A, SN74AS646, and SN74AS648 are characterized for operation from 0°C to 70°C.



SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

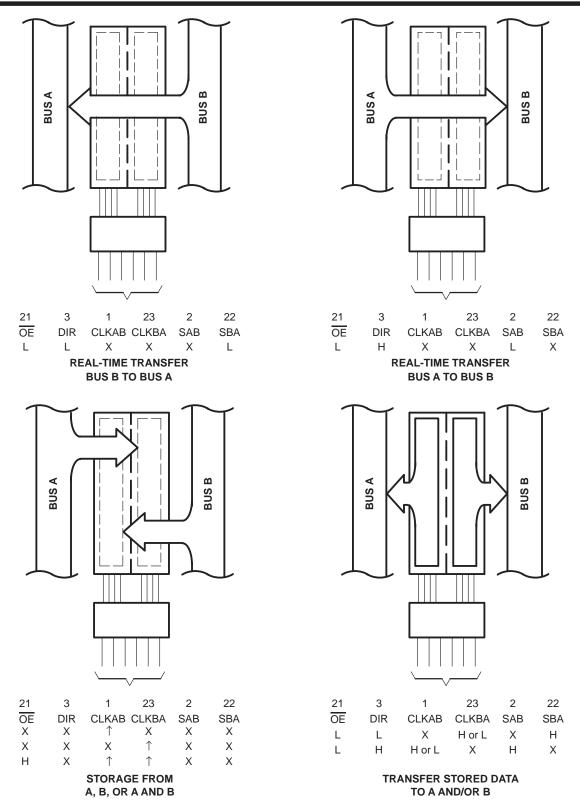


Figure 1. Bus-Management Functions

Pin numbers shown are for the DW, JT, and NT packages.



SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

Function Tables

SN54ALS646, SN54AS646, SN74ALS646A, SN74AS646

		INP	UTS			DAT	A I/O	OPERATION OR FUNCTION
OE	DIR	CLKAB	CLKBA	SAB	SBA	A1-A8	B1-B8	OPERATION OR FUNCTION
Х	Х	1	Χ	Х	Χ	Input	Unspecified [†]	Store A, B unspecified [†]
Х	X	Χ	\uparrow	Χ	Χ	Unspecified [†]	Input	Store B, A unspecified [†]
Н	Х	1	↑	Х	Х	Input	Input	Store A and B data
Н	X	H or L	H or L	Χ	Χ	Input disabled	Input disabled	Isolation, hold storage
L	L	Х	Х	Х	L	Output	Input	Real-time B data to A bus
L	L	Χ	H or L	Χ	Н	Output	Input	Stored B data to A bus
L	Н	Х	Χ	L	Χ	Input	Output	Real-time A data to B bus
L	Н	H or L	X	Н	Χ	Input	Output	Stored A data to B bus

[†] The data output functions can be enabled or disabled by various signals at $\overline{\text{OE}}$ and DIR. Data input functions are always enabled; i.e., data at the bus terminals is stored on every low-to-high transition of the clock inputs.

SN54ALS648, SN74ALS648A, SN74AS648

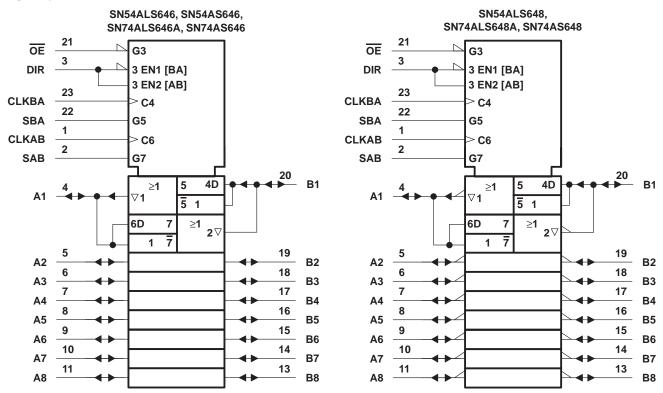
		INP	UTS			DAT	A I/O	OPERATION OR FUNCTION
OE	DIR	CLKAB	CLKBA	SAB	SBA	A1-A8	B1-B8	OPERATION OR FUNCTION
Х	Х	1	Х	Х	Х	Input	Unspecified [†]	Store A, B unspecified [†]
Х	X	Χ	1	X	Χ	Unspecified [†]	Input	Store B, A unspecified [†]
Н	Х	1	1	Х	Χ	Input	Input	Store A and B data
Н	Х	H or L	H or L	Χ	Χ	Input disabled	Input disabled	Isolation, hold storage
L	L	Х	Х	Х	L	Output	Input	Real-time B data to A bus
L	L	Χ	H or L	Χ	Н	Output	Input	Stored \overline{B} data to A bus
L	Н	Х	Х	Ĺ	Х	Input	Output	Real-time \overline{A} data to B bus
L	Н	H or L	Χ	Н	Χ	Input	Output	Stored \overline{A} data to B bus

[†] The data output functions can be enabled or disabled by various signals at $\overline{\text{OE}}$ and DIR. Data input functions are always enabled; i.e., data at the bus terminals is stored on every low-to-high transition of the clock inputs.



SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

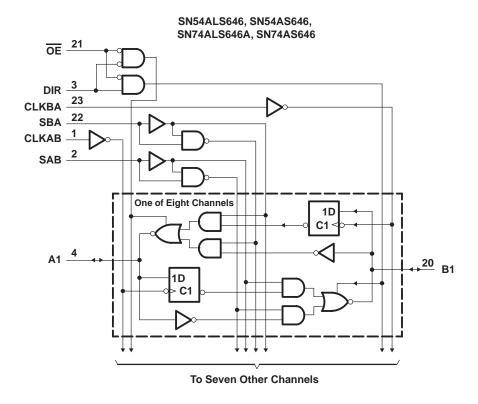
logic symbols†

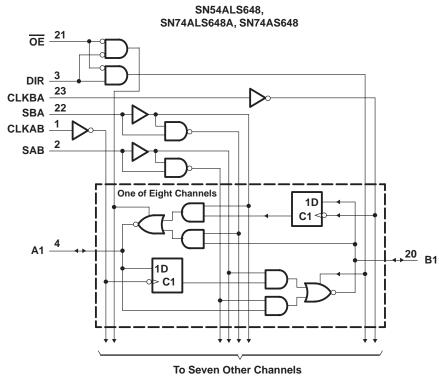


[†]These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the DW, JT, and NT packages.



logic diagrams (positive logic)





Pin numbers shown are for the DW, JT, and NT packages.



SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}			. 7 V
Input voltage, V _I : Control inputs			. 7 V
I/O ports			5.5 V
Operating free-air temperature range, TA:	SN54ALS646	−55°C to	125°C
	SN74ALS646A	0°C to	70°C
Storage temperature range		−65°C to	150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN	54ALS6	46	SN7	'4ALS64	6A	LINUT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
Vсс	Supply voltage	4.5	5	5.5	4.5	5	5.5	V	
VIH	High-level input voltage	2			2			V	
\vee_{IL}	Low-level input voltage			0.7			0.8	V	
ЮН	High-level output current			-12			-15	mA	
	Low-level output current			12			24	4	
lOL							48‡	mA	
fclock	Clock frequency	0		35	0		40	MHz	
t _W	Pulse duration, CLKBA or CLKAB high or low	14.5			12.5			ns	
t _{su}	Setup time, A before CLKAB↑ or B before CLKBA↑	15			10			ns	
t _h	Hold time, A after CLKAB↑ or B after CLKBA↑	0			0			ns	
TA	Operating free-air temperature	-55		125	0		70	°C	

[‡] Applies only to the -1 version and only if V_{CC} is maintained between 4.75 V and 5.25



SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	DADAMETED	TEST COL	IDITIONS	SN	54ALS6	46	SN7	4ALS64	6A	UNIT
'	PARAMETER	TEST CON	IDITIONS	MIN	TYP†	MAX	MIN	TYP†	MAX	UNII
VIK		V _{CC} = 4.5 V,	$I_{I} = -18 \text{ mA}$			-1.2			-1.2	V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2			V _{CC} -2			
\/a			$I_{OH} = -3 \text{ mA}$	2.4	3.2		2.4	3.2		V
VOH			$I_{OH} = -12 \text{ mA}$	2						V
			$I_{OH} = -15 \text{ mA}$				2			
			I _{OL} = 12 mA		0.25	0.4		0.25	0.4	
VOL		-	I _{OL} = 24 mA					0.35	0.5	V
			$I_{OL} = 48 \text{ mA}^{\ddagger}$					0.35	0.5	
П	Control inputs	V00 = 5.5 V	V _I = 7 V			0.1			0.1	mA
''	A or B ports	V _{CC} = 5.5 V	V _I = 5.5 V			0.1			0.1	ША
	Control inputs	\/	V: 07V			20			20	^
ΊΗ	A or B ports§	V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μΑ
	Control inputs	V 55V	V 0.4V			-0.2			-0.2	4
IIL.	A or B ports§	V _{CC} = 5.5 V,	$V_{I} = 0.4 V$			-0.2			-0.2	mA
IO¶		V _{CC} = 5.5 V,	V _O = 2.25 V	-20		-112	-30		-112	mA
			Outputs high		47	76		47	76	
ICC		<u> </u>	Outputs low		55	88		55	88	mA
			Outputs disabled		55	88		55	88	

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

 $[\]ddagger$ Applies only to the -1 version and only if VCC is maintained between 4.75 V and 5.25 \$ For I/O ports, the parameters I_{IH} and I_{IL} include the off-state output current.

¹ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _C C _L R1 R2 T _A	UNIT			
			SN54A	LS646	SN74AL	S646A	
			MIN	MAX	MIN	MAX	
f _{max}			35		40		MHz
^t PLH	CLKBA or CLKAB	A or B	10	35	7	30	ns
^t PHL	CENDA OF CENAD	AOIB	5	20	5	17	115
^t PLH	A or B	B or A	5	22	3	20	ns
^t PHL		DUIA	3	15	3	12	113
^t PLH	SBA or SAB [‡] (stored data low)	A or B	10	40	7	35	ns
^t PHL		7 01 15	5	23	5	20	113
^t PLH	SBA or SAB‡	A or B	8	30	6	25	ns
^t PHL	(stored data high)	AOIB	5	24	5	20	ns
^t PZH	ŌĒ	A or B	3	20	2	17	ns
^t PZL	OE	AOIB	5	22	4	20	115
^t PHZ	ŌĒ	A or B	1	12	1	10	ns
^t PLZ	OE	AOIB	1	20	2	16	115
^t PZH	DIR	A or B	5	38	3	30	ns
t _{PZL}	DIK	AUIB	5	30	4	25	115
^t PHZ	DIR	A or B	1	12	1	10	ns
^t PLZ	אוט	AUIB	2	21	2	16	115

[†] For conditions shown MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] These parameters are measured with the internal output state of the storage register opposite that of the bus input.

SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}			. 7 V
Input voltage, V _I : Control inputs			. 7 V
I/O ports			5.5 V
Operating free-air temperature range, T _A :	SN54ALS648	-55°C to	125°C
	SN74ALS648A	0°C to	o 70°C
Storage temperature range		-65°C to	150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN	54ALS6	SN74ALS648A			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.7			0.8	V
IOH	High-level output current			-12			-15	mA
loL	Low-level output current			12			24	mA
fclock	Clock frequency	0		35	0		40	MHz
t _W	Pulse duration, CLKBA or CLKAB high or low	14.5			12.5			ns
t _{su}	Setup time, A before CLKAB↑ or B before CLKBA↑	15			10			ns
t _h	Hold time, A after CLKAB↑ or B after CLKBA↑	0			0			ns
TA	Operating free-air temperature	-55		125	0		70	°C

SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CO	NDITIONS	SN	54ALS6	48	SN7	4ALS64	8A	UNIT
	PARAMETER	lesi co	NUTTIONS	MIN	TYP [†]	MAX	MIN	TYP [†]	MAX	UNII
٧ıK		V _{CC} = 4.5 V,	I _I = -18 mA			-1.2			-1.2	V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2			V _{CC} -2			
V/011			$I_{OH} = -3 \text{ mA}$	2.4	3.2		2.4	3.2		V
VOH		V _{CC} = 4.5 V	$I_{OH} = -12 \text{ mA}$	2						V
			$I_{OH} = -15 \text{ mA}$				2			
V		V _{CC} = 4.5 V	I _{OL} = 12 mA		0.25	0.4		0.25	0.4	V
VOL		VCC = 4.5 V	I _{OL} = 24 mA					0.35	0.5	V
i.	Control inputs	V00 - 5 5 V	V _I = 7 V			0.1			0.1	mA
l _l	A or B ports	V _{CC} = 5.5 V	V _I = 5.5 V			0.1			0.1	
	Control inputs	V 55V	V 07V			20			20	^
ΊΗ	A or B ports‡	V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μΑ
	Control inputs	V 55V)/ 0.4\/			-0.2			-0.2	^
lIL.	A or B ports‡	V _{CC} = 5.5 V,	V _I = 0.4 V			-0.2			-0.2	mA
ΙΟ§		V _{CC} = 5.5 V,	V _O = 2.25 V	-20		-112	-30		-112	mA
			Outputs high		47	76		47	76	
Icc		V _{CC} = 5.5 V	Outputs low		57	88		57	88	mA
			Outputs disabled		57	88		57	88	

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

For I/O ports, the parameters I_{IH} and I_{IL} include the off-state output current.

[§] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _C C _L R1 R2 T _A	UNIT			
			SN54A	LS648	SN74AL	S648A	
			MIN	MAX	MIN	MAX	
f _{max}			35		40		MHz
^t PLH	CLKBA or CLKAB	A or B	8	39	7	33	ns
^t PHL	CENDA OF CENAD	AOID	5	23	5	20	113
^t PLH	A or B	B or A	3	20	2	17	ns
^t PHL		DOIN	2	12	2	10	113
^t PLH	SBA or SAB‡	A or B	5	44	5	39	ns
^t PHL	(stored data low)	7010	4	26	4	22	113
^t PLH	SBA or SAB‡	A or B	6	30	6	25	ns
^t PHL	(stored data high)	AOID	6	25	6	21	113
^t PZH	ŌĒ	A or B	4	25	2	22	ns
^t PZL	OE	AOID	4	25	4	22	113
^t PHZ	ŌĒ	A or B	1	12	1	10	ns
^t PLZ	OE .	7015	2	21	2	15	110
^t PZH	DIR	A or B	4	35	2	27	ns
^t PZL	DIIX	7015	3	25	3	19	110
^t PHZ	DIR	A or B	1	17	1	14	ns
t _{PLZ}	DIK	7016	2	22	2	15	115

[†] For conditions shown MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] These parameters are measured with the internal output state of the storage register opposite that of the bus input.

SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}			. 7 V
Input voltage, V _I : Control inputs			. 7 V
I/O ports			5.5 V
Operating free-air temperature range, TA:	: SN54AS646	−55°C to	125°C
	SN74AS646	0°C to	o 70°C
Storage temperature range		-65°C to	150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

			SI	N54AS64	16	SN74AS646		6	UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
Vcc	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage		2			2			V
V_{IL}	Low-level input voltage				0.8			0.8	V
loh	High-level output current				-12			-15	mA
loL	Low-level output current				32			48	mA
f _{clock} *	Clock frequency		0		75	0		90	MHz
4 *	Pulse duration \vdash	CLKBA or CLKAB high	6			5			ns
t _W *		CLKBA or CLKAB low	7			6			
t _{su} *	Setup time, A before CLKAB↑ or B before CLKBA↑		7			6			ns
t _h *	Hold time, A after CLKAB↑ or B before CLKBA		0			0			ns
TA	Operating free-air temperature		-55		125	0		70	°C

^{*} On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.

SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		SN	54AS64	l6	SN74AS646			UNIT	
				MIN	TYP†	MAX	MIN	TYP†	MAX	CINIT	
٧ıK		V _{CC} = 4.5 V,	I _I = -18 mA			-1.2			-1.2	V	
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -2 \text{ mA}$	V _{CC} -2			V _{CC} -2				
\/a			$I_{OH} = -3 \text{ mA}$	2.4	3.2		2.4	3.2		V	
VOH		$V_{CC} = 4.5 \text{ V}$	$I_{OH} = -12 \text{ mA}$	2						V	
			$I_{OH} = -15 \text{ mA}$				2				
\/0:		V00 = 4.5.V	I _{OL} = 32 mA		0.25	0.5				V	
VOL		V _{CC} = 4.5 V	I _{OL} = 48 mA					0.35	0.5		
ı	Control inputs	V _{CC} = 5.5 V,	V _I = 7 V			0.1			0.1	mA	
Ħ	A or B ports	V _{CC} = 5.5 V,	V _I = 5.5 V			0.1			0.1	IIIA	
	Control inputs	\/	V _I = 2.7 V			20			20	^	
IН	A or B ports‡	V _{CC} = 5.5 V,				70			70	μΑ	
	Control input	V 55V				-0.5			-0.5		
IIL	A or B ports‡	V _{CC} = 5.5 V,	$V_{CC} = 5.5 \text{ V}, \qquad V_{I} = 0.4$	V _I = 0.4 V			-0.75			-0.75	mA
ΙΟ§		V _{CC} = 5.5 V,	V _O = 2.25 V	-30		-112	-30		-112	mA	
			Outputs high		120	195		120	195		
Icc		V _{CC} = 5.5 V Outputs low Outputs disabled	Outputs low		130	211		130	211	mA	
				130	211		130	211			

 $[\]overline{\dagger}$ All typical values are at V_{CC} = 5 V, T_A = 25 °C.

[‡] For I/O ports, the parameters I_{IH} and I_{IL} include the off-state output current.

[§] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R1 = 500 Ω , R2 = 500 Ω , T_A = MIN to MAX †				UNIT
			SN54AS646		SN74AS646		1
			MIN	MAX	MIN	MAX	
f _{max} *			75		90		MHz
^t PLH	CLKBA or CLKAB	A or B	2	9.5	2	8.5	ns
^t PHL		A 01 B	2	10	2	9	113
^t PLH	A or B	B or A	2	11.5	2	9	ns
^t PHL		DUIA	1	8	1	7	113
^t PLH	004 04B‡	A or B	2	13.5	2	11	ns
^t PHL	SBA or SAB‡	AOID	2	11	2	9	113
^t PZH	ŌĒ	A or B	2	11	2	9	ns
tPZL	OE .	A 01 B	3	15	3	14	113
^t PHZ	ŌĒ	A or B	2	11	2	9	ns
^t PLZ	OE	AUD	2	11	2	9	113
^t PZH	DIR	A or B	3	21	3	16	ns
t _{PZL}		7010	3	24	3	18	115
[†] PHZ	DIR	A or B	2	12	2	10	ns
^t PLZ	DIK	A 01 B	2	12	2	10	115

^{*} On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.

[†] For conditions shown MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] These parameters are measured with the internal output state of the storage register opposite that of the bus input.

SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}		7 V
Input voltage, V _I : Control inputs		7 V
I/O ports		5.5 V
Operating free-air temperature range, T _A : SN74AS648	. 0°C to	70°C
Storage temperature range	-65°C to 1	150°C

recommended operating conditions

			SI	SN74AS648		
			MIN	NOM	MAX	UNIT
Vcc	Supply voltage		4.5	5	5.5	V
VIH	High-level input voltage		2			V
V _{IL}	Low-level input voltage				0.8	V
ІОН	High-level output current				-15	mA
lOL	Low-level output current				48	mA
fclock	Clock frequency		0		90	MHz
	Pulse duration	CLKBA or CLKAB high	5			no
t _W	Pulse duration	CLKBA or CLKAB low	6			ns
t _{su}	Setup time, A before CLKAB↑ or B before CLKBA↑		6			ns
th	Hold time, A after CLKAB↑ or B before CLKBA		0			ns
TA	Operating free-air temperature		0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		SN	SN74AS648			
	PARAMETER	TEST COND	TEST CONDITIONS		TYP‡	MAX	UNIT	
٧ıK		$V_{CC} = 4.5 V,$	$I_{I} = -18 \text{ mA}$			-1.2	V	
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -2 \text{ mA}$	V _{CC} -2				
۷он		V 45V	IOH = -3 mA	2.4	3.2		V	
		$V_{CC} = 4.5 \text{ V}$	$I_{OH} = -15 \text{ mA}$	2				
VOL		$V_{CC} = 4.5 V,$	I _{OL} = 48 mA		0.35	0.5	V	
1.	Control inputs	V _{CC} = 5.5 V	V _I = 7 V			0.1	A	
'1	A or B ports		V _I = 5.5 V			0.1	mA	
	Control inputs	V _{CC} = 5.5 V,	V _I = 2.7 V			20		
lін	A or B ports§					70	μΑ	
	Control input	V _{CC} = 5.5 V,				-0.5		
IIL	A or B ports§		V _I = 0.4 V			-0.75	mA	
Io¶		V _{CC} = 5.5 V,	V _O = 2.25 V	-30		-112	mA	
			Outputs high		110	185		
Icc		$V_{CC} = 5.5 V$	Outputs low		120	195	mA	
			Outputs disabled		120	195		

 $[\]ddagger$ All typical values are at V_{CC} = 5 V, T_A = 25 °C.

The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.



[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

[§] For I/O ports, the parameters I_{IH} and I_{IL} include the off-state output current.

SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 4.5 C _L = 50 pF R1 = 500 Ω R2 = 500 Ω T _A = MIN t	UNIT	
			SN74		
			MIN	MAX	
f _{max}			90		MHz
^t PLH	CLKBA or CLKAB	A or B	2	8.5	ns
^t PHL		AUB	2	9	115
^t PLH	A or B	B or A	2	8	ns
^t PHL		BULA	1	7	115
^t PLH	SBA or SAB‡	A or B	2	11	ns
^t PHL	SBA OF SAB+	AUB	2	9	115
^t PZH	ŌĒ	A or B	2	9	ns
^t PZL	OE OE	AUB	3	15	115
^t PHZ	ŌĒ	A or B	2	9	ns
t _{PLZ}] OE	AGIB	2	9	113
^t PZH	DIR	A or B	3	16	ns
^t PZL	- DIK		3	18	1115
^t PHZ	DIR	A or B	2	10	ns
t _{PLZ}	DIK	A 01 B	2	10	115

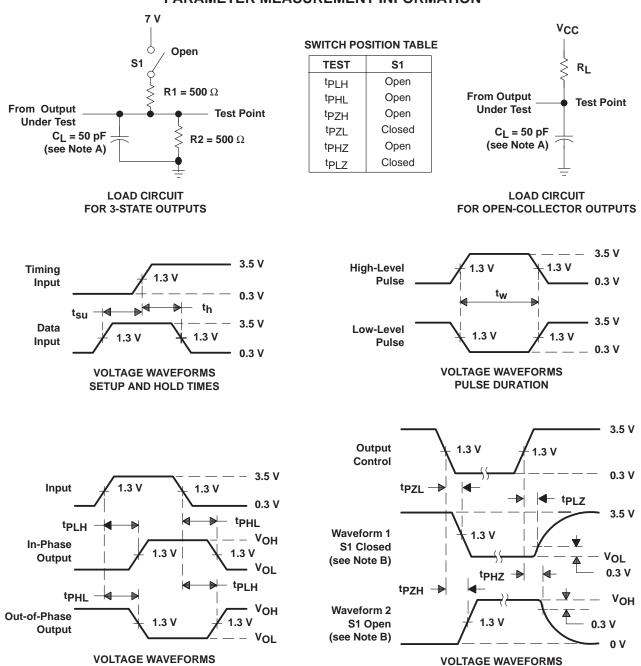
[†] For conditions shown MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] These parameters are measured with the internal output state of the storage register opposite that of the bus input.

SDAS039F - DECEMBER 1983 - REVISED JANUARY 1995

ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

PROPAGATION DELAY TIMES

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \ \Omega$, $t_f \leq$ 2 ns, $t_f \leq$ 2 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 2. Load Circuits and Voltage Waveforms



IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 1998, Texas Instruments Incorporated